

## PATENT APPLICATION

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[Title]	Semiconductor device and test method of testing the same
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[Request for Examination] Requested

[Application Order] We respectively submit an application according to Art. 42 of the Patent Law and request an examination according to Art. 60 of the Patent Law, as above.

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[Fee]

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[Enclosures]

1. Abstract and Specification ( and Drawings) 1 copy each